

<b>Notice of References Cited</b>	Application/Control No. 10/551,233		Applicant(s)/Patent Under Reexamination FUKUNAGA ET AL.	
	Examiner Bijan Ahvazi		Art Unit 1796	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,526,711 A	07-1985	Sacher et al.	252/582
*	B	US-4,559,147 A	12-1985	Hirth et al.	252/1
*	C	US-4,789,490 A	12-1988	Tanaka, Toshiaki	252/408.1
*	D	US-5,817,256 A	10-1998	Weippert, Hans-Joachim	252/582
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	SU 168825	01-1962	Russian	Sergeev et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yerina, Natalya; Magonov, Sergei, Atomic force microscopy in analysis of rubber materials, Rubber Chemistry and Technology (2003), 76(4), 846-859, American Chemical Society, Rubber Division Journal.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.